

N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)			
40	0.0022 at V _{GS} = 10 V	62	28 nC			
	0.0038 at V _{GS} = 4.5 V	35	20110			

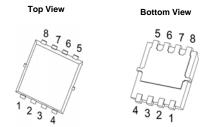
FEATURES

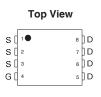
- TrenchFET II Power MOSFET
- 100 % R_{α} and UIS Tested

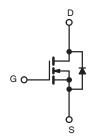


APPLICATIONS

- Notebook PC Core
- VRM/POL







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	40	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		62 ^{a, e}	A	
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	I _D	50 ^e		
Continuous Diain Culterit (1) = 173 C)	T _A = 25 °C	טי	21 ^{b, c}		
	T _A = 70 °C		16 ^{b, c}		
Pulsed Drain Current	I _{DM}	248			
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	58		
Single Pulse Avalanche Energy	L = 0.1 11111	E _{AS}	135	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	62 ^{a, e}	A	
Continuous Gource-Drain Diode Current	T _A = 25 °C	'S	35 ^{b, c}		
	T _C = 25 °C		92	w	
Maximum Power Dissipation	T _C = 70 °C	P _D	70		
Maximum Fower Dissipation	T _A = 25 °C	' D	6.3 ^{b, c}		
	T _A = 70 °C		4.1 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	40	50	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	16	20	G/ VV		

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
 c. t = 10 s.
 d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 µA		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 – 200 μΑ		- 5.5		IIIV/ C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zoro Coto Voltogo Drain Current	la a a	V _{DS} = 32 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 32 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	62			Α
D : 0	D.	V _{GS} = 10 V, I _D = 20 A		0.0022 0.0032		0
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 15 A		0.0038	0.0045	Ω
Forward Transconductance ^a	g _{fs}	$V_{DS} = 32V, I_{D} = 10 A$		70		S
Dynamic ^b				•		
Input Capacitance	C _{iss}	Т		1950		
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		558		pF
Reverse Transfer Capacitance	C _{rss}			52		
Total Gate Charge		$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		28		nC
	Q _g			15		
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		6		
Gate-Drain Charge	Q _{gd}			3		
Gate Resistance	R_g	f = 1 MHz		1.5	2.5	Ω
Turn-On Delay Time	t _{d(on)}			15		
Rise Time	t _r	V_{DD} = 20 V, R_L = 0.555 Ω		10		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 20$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		30		
Fall Time	t _f			8		20
Turn-On Delay Time	t _{d(on)}			35		ns
Rise Time	t _r	V_{DD} = 20 V, R_L = 0.625 Ω		60]
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 15 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		25		
Fall Time	t _f			8		
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			62	۸
Pulse Diode Forward Current ^a	I _{SM}				248	Α
Body Diode Voltage	V _{SD}	I _S = 12 A		0.7	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}	Q _{rr}		63	95	nC
Reverse Recovery Fall Time t _a		$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		21		ns
Reverse Recovery Rise Time	t _b	7		20		

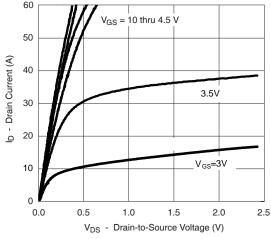
Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

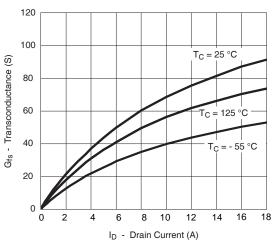
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



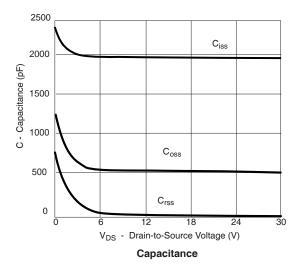
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

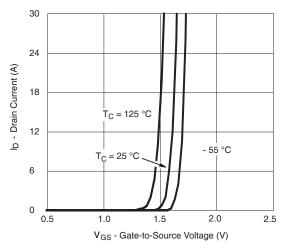


Output Characteristics

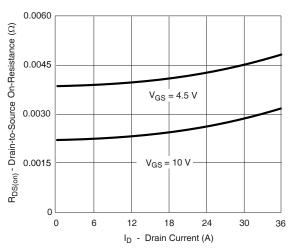


Transconductance

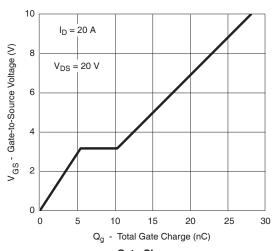




Transfer Characteristics



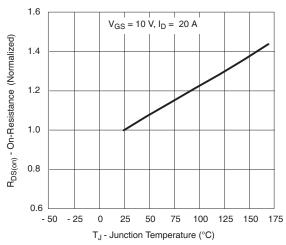
R_{DS(on)} vs. Drain Current



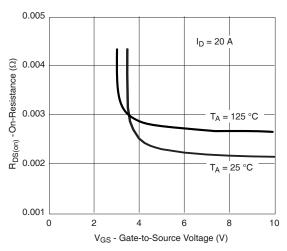
Gate Charge



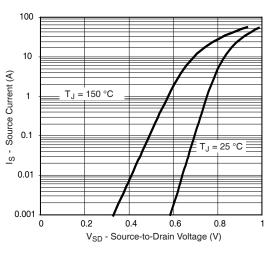
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



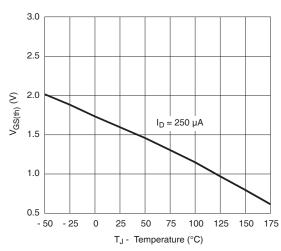
On-Resistance vs. Junction Temperature



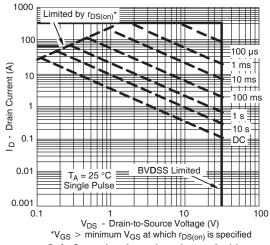
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature

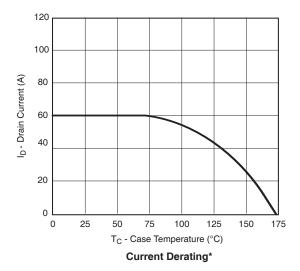


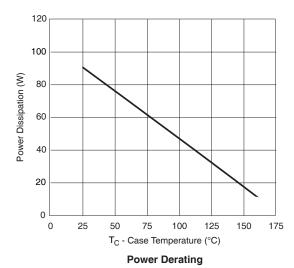
Threshold Voltage



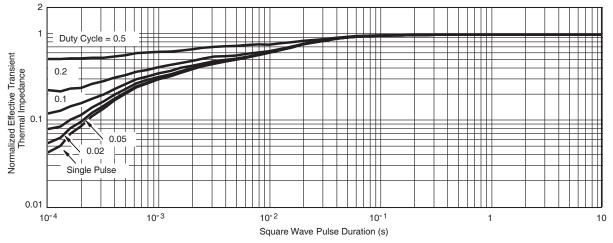
Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





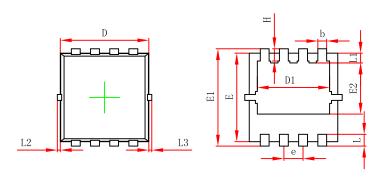
* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case

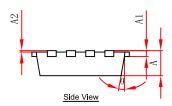


PDFN3.3x3.3-8L Package Outline Dimensions



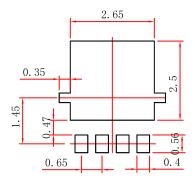


Bottom View



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
Α	0.650	0.850	0.026	0.033	
A1	0.152	REF.	0.006	REF.	
A2	0~0).05	0~0.002		
D	2.900	3.100	0.114	0.122	
D1	2.300	2.600	0.091	0.102	
E	2.900	3.100	0.114	0.122	
E1	3.150	3.450	0.124	0.136	
E2	1.535	1.935	0.060	0.076	
b	0.200	0.400	0.008	0.016	
е	0.550	0.750	0.022	0.030	
L	0.300	0.500	0.012	0.020	
L1	0.180	0.480	0.007	0.019	
L2	0~0.100		0~0	0~0.004	
L3	0~0.100		0~0	0~0.004	
Н	0.315	0.515	0.012	0.020	
θ	9°	13°	9°	13°	

PDFN3.3x3.3-8L Suggested Pad Layout







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